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Contents

v Conference Committee

SESSION 1 ASTRONOMICAL X-RAY OPTICS I

12576 02 Grazing incidence x-ray optics in the Czech Republic: past, present, future [12576-1]

SESSION 2 ASTRONOMICAL X-RAY OPTICS II

12576 03	Imaging performance above 150 keV of the wide field monitor on board the ASTENA concept mission [12576-3]
12576 04	Novel lobster eye and Kirkpatrick Baez modules based on multi foil technology: design, assembly, and tests [12576-5]
12576 05	CubeSat microsatellite demonstrator with x-ray optical payload [12576-24]
12576 06	Testing of lobster-eye type telescopes with x-rays and visible light [12576-6]
SESSION 3	MULTILAYER X-RAY OPTICS
12576 08	Development of multilayer gratings for Solar-C EUV spectro-imager [12576-8]

12576 09 LOPSIMUL: quick numerical simulator of multi-foil reflective optical system [12576-25]

SESSION 4 X-RAY OPTICS: A HISTORICAL REVIEW

- 12576 0A A guided tour of the Deutsches Röntgen-Museum: displaying X-ray history [12576-10]
- 12576 OB The Röntgen Medal: honouring x-ray excellence [12576-11]

SESSION 5 LABORATORY X-RAY/EUV OPTICS

12576 OC	Soft x-ray spectroscopy in the lab with an ellipsoidal mirror and a wavefront corrected reflection zone plate [12576-14]
12576 OD	Microfocus laboratory soft x-ray source for vacuum optical test facilities [12576-20]
SESSION 6	INTEGRATED DEVICES
12576 OE	The stitching interferometry system of ALBA [12576-15]
SESSION 7	REFRACTIVE AND DIFFRACTIVE X-RAY OPTICS
12576 OF	Anodic bonding to manufacture LAUE lenses for high-energy astrophysics [12576-18]
12576 OF 12576 OG	Anodic bonding to manufacture LAUE lenses for high-energy astrophysics [12576-18] Achromatic x-ray lenses based on low-Z hydride compounds [12576-19]
12576 OF 12576 OG	Anodic bonding to manufacture LAUE lenses for high-energy astrophysics [12576-18] Achromatic x-ray lenses based on low-Z hydride compounds [12576-19]
12576 OF 12576 OG	Anodic bonding to manufacture LAUE lenses for high-energy astrophysics [12576-18] Achromatic x-ray lenses based on low-Z hydride compounds [12576-19] POSTER SESSION

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